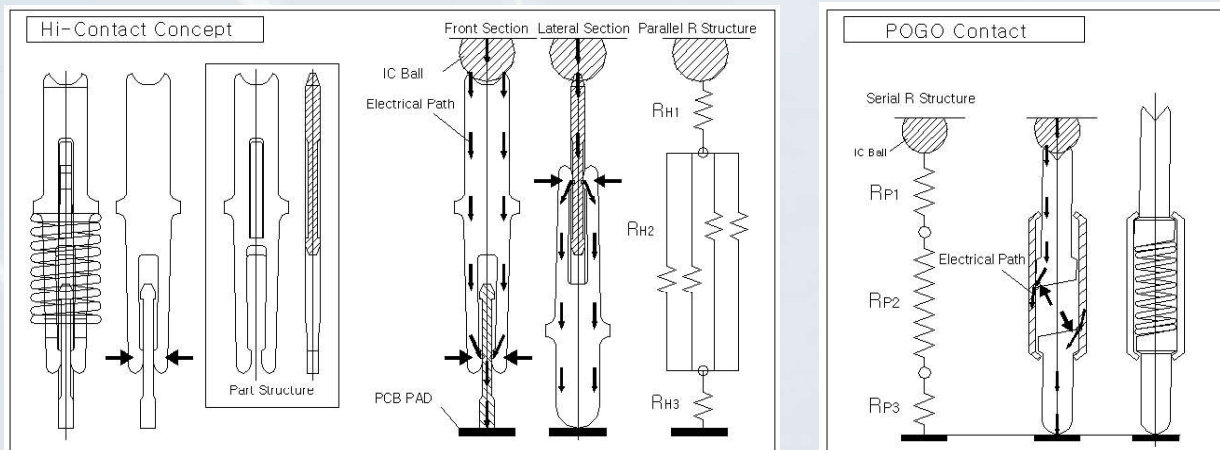




Lower cost and more reliable spring probe pin test solution

What makes Hi-Contact superior to conventional spring probe pins?



- Parallel connection: Multiple contact points between upper and lower plungers keeps contact resistance lower while conventional spring probe pins only have a single contact point.
- Hi-Contact provides consistent test quality with excellent contact resistance.
- Stamped plungers reduce component prices and improves productivity.
- Simple mechanism enables mass production and better pin quality
- High volume manufacturing processes reduce the pin price. (PATENT : US 7,025,602 B1)

HiCon provides various types of customized test sockets. Our design capability enables us to create optimized solutions for customer's special application requirements. Whatever application you have, HiCon is ready with the best solution for your needs.